

*“Quantitative HAADF STEM of SiGe in presence of amorphous surface layers from FIB preparation”.* Grieb T, Tewes M, Schowalter M, Müller-Caspary K, Krause FF, Mehrtens T, Hartmann J-M, Rosenauer A, Ultramicroscopy **184**, 29 (2018).  
<http://doi.org/10.1016/J.ULTRAMIC.2017.09.012>